

RMLV0808BGSB - 4S2

8Mb Advanced LPSRAM (1024k word × 8bit)

R10DS0232EJ0200 Rev.2.00 2015.06.26

Description

The RMLV0808BGSB is a family of 8-Mbit static RAMs organized 1,048,576-word × 8-bit, fabricated by Renesas's high-performance Advanced LPSRAM technologies. The RMLV0808BGSB has realized higher density, higher performance and low power consumption. The RMLV0808BGSB offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is offered in 44pin TSOP (II).

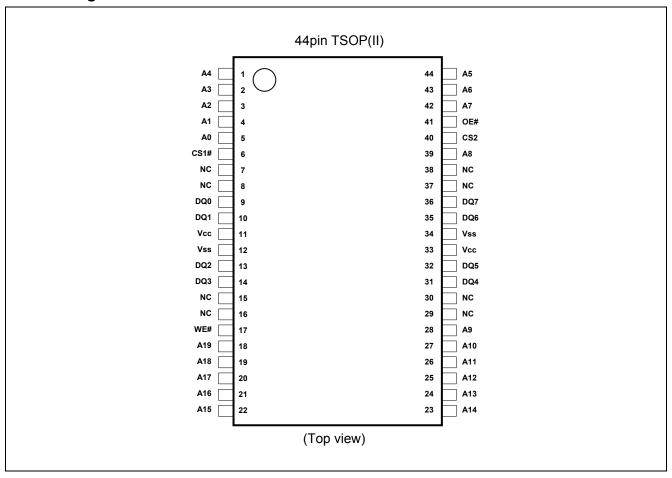
Features

- Single 3V supply: 2.4V to 3.6V
- Access time:
 - Power supply voltage from 2.7V to 3.6V: 45ns (max.)
 - Power supply voltage from 2.4V to 2.7V: 55ns (max.)
- Current consumption:
 - Standby: 0.45μA (typ.)
- Equal access and cycle times
- Common data input and output
 - Three state output
- Directly TTL compatible
 - All inputs and outputs
- Battery backup operation

Part Name Information

| Part Name | Power supply | Access time | Temperature Range | Package | |
|----------------------|--------------------|-------------|----------------------|--|--|
| RMLV0808BGSB-4S2 | 2.7V to 3.6V 45 ns | | -40 ~ +85°C | 44.70mm,40.44mm,44min,nlootia,TCOD(II) | |
| RIVIL V UOUODGSD-432 | 2.4V to 2.7V | 55 ns | -40 ~ +65 C | 11.76mm×18.41mm 44pin plastic TSOP(II) | |

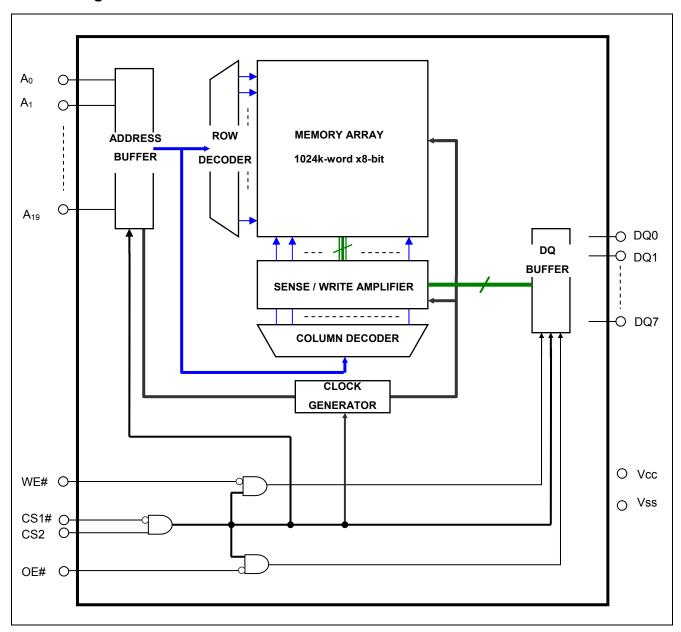
Pin Arrangement



Pin Description

| Pin name | Function |
|-----------------|-------------------|
| V _{CC} | Power supply |
| V _{SS} | Ground |
| A0 to A19 | Address input |
| DQ0 to DQ7 | Data input/output |
| CS1# | Chip select 1 |
| CS2 | Chip select 2 |
| OE# | Output enable |
| WE# | Write enable |
| NC | No connection |

Block Diagram



Operation Table

| CS1# | CS2 | WE# | OE# | DQ0~7 | Operation |
|------|-----|-----|-----|--------|----------------|
| Н | Χ | Х | Χ | High-Z | Stand-by |
| Х | L | Х | Х | High-Z | Stand-by |
| L | Н | L | Х | Din | Write |
| L | Н | Н | L | Dout | Read |
| L | Н | Н | Н | High-Z | Output disable |

Note 1. H: V_{IH} L:V_{IL} X: V_{IH} or V_{IL}

Absolute Maximum Ratings

| Parameter | Symbol | Value | unit |
|---|-----------------|--|------|
| Power supply voltage relative to V _{SS} | V _{CC} | -0.5 to +4.6 | V |
| Terminal voltage on any pin relative to V _{SS} | V _T | -0.5 ^{*2} to V _{CC} +0.3 ^{*3} | V |
| Power dissipation | P _T | 0.7 | W |
| Operation temperature | Topr | -40 to +85 | °C |
| Storage temperature range | Tstg | -65 to +150 | °C |
| Storage temperature range under bias | Tbias | -40 to +85 | °C |

Note 2. -3.0V for pulse ≤ 30ns (full width at half maximum)

3. Maximum voltage is +4.6V.

DC Operating Conditions

| Parameter | Symbol | Min. | Тур. | Max. | Unit | Test conditions | Note |
|---------------------------|----------|------|------|----------------------|------|------------------|------|
| Supply voltage | Vcc | 2.4 | 3.0 | 3.6 | V | | |
| | Vss | 0 | 0 | 0 | V | | |
| land bink waltana | | 2.0 | _ | V _{CC} +0.2 | V | Vcc=2.4V to 2.7V | |
| Input high voltage | V_{IH} | 2.2 | _ | V _{CC} +0.2 | V | Vcc=2.7V to 3.6V | |
| la anti-mark | \ / | -0.2 | _ | 0.4 | V | Vcc=2.4V to 2.7V | 4 |
| Input low voltage | V_{IL} | -0.2 | _ | 0.6 | V | Vcc=2.7V to 3.6V | 4 |
| Ambient temperature range | Та | -40 | _ | +85 | °C | | |

Note 4. -3.0V for pulse \leq 30ns (full width at half maximum)

DC Characteristics

| Parameter | Symbol | Min. | Тур. | Max. | Unit | Test conditions | | | |
|---------------------------|------------------|------|--------------------|------|------|--|--|--|--|
| Input leakage current | | ı | _ | 1 | μА | Vin = V _{SS} to V _{CC} | | | |
| Output leakage current | I _{LO} | ı | _ | 1 | μА | CS1# = V_{IH} or CS2 = V_{IL} or OE# = V_{IH} or WE# = V_{IL} , $V_{I/O}$ = V_{SS} to V_{CC} | | | |
| Average operating current | | - | 20 ^{*5} | 25 | mA | , | 55ns, duty =100%, I _{I/O} = 0mA, / _{IL} , CS2 = V _{IH} , Others = V _{IH} /V _{IL} | | |
| | I _{CC1} | I | 25 ^{*5} | 30 | mA | _ | I5ns, duty =100%, I _{I/O} = 0mA, I _{IL} , CS2 = V _{IH} , Others = V _{IH} /V _{IL} | | |
| | I _{CC2} | - | 1.5 ^{*5} | 3 | mA | Cycle = $1\mu s$, duty = 100% , $I_{I/O} = 0mA$, CS1# $\leq 0.2V$, CS2 $\geq V_{CC} - 0.2V$, $V_{IH} \geq V_{CC} - 0.2V$, $V_{IL} \leq 0.2V$ | | | |
| Standby current | I _{SB} | _ | _ | 0.3 | mA | CS2 = V _I | $_{L}$, Others = V_{SS} to V_{CC} | | |
| Standby current | | - | 0.45 ^{*5} | 2 | μА | ~+25°C | | | |
| | | ı | 0.6 ^{*6} | 4 | μА | ~+40°C | Vin = V_{SS} to V_{CC} , (1) CS2 \leq 0.2V or | | |
| | I _{SB1} | ı | _ | 7 | μА | ~+70°C | (2) CS1# ≥ V _{CC} -0.2V, CS2 ≥ V _{CC} -0.2V | | |
| | | ı | _ | 10 | μΑ | ~+85°C | | | |
| Output high voltage | V _{OH} | 2.4 | _ | _ | ٧ | I _{OH} = -1mA Vcc≥2.7V | | | |
| | V _{OH2} | 2.0 | _ | | V | I _{OH} = -0.1 | mA | | |
| Output low voltage | V _{OL} | _ | _ | 0.4 | ٧ | I _{OL} = 2mA Vcc≥2.7V | | | |
| No. 5 Trial and the | V _{OL2} | _ | _ | 0.4 | V | I _{OL} = 0.1r | mA (T. 0500) and a 14000/ (and a | | |

Note 5. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=25°C), and not 100% tested.

Note 6. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=40°C), and not 100% tested.

Capacitance

(Ta = 25° C, f =1MHz)

| Parameter | Symbol | Min. | Тур. | Max. | Unit | Test conditions | Note |
|----------------------------|------------------|------|------|------|------|----------------------|------|
| Input capacitance | C in | _ | _ | 8 | pF | Vin =0V | 7 |
| Input / output capacitance | C _{I/O} | ı | 1 | 10 | pF | V _{I/O} =0V | 7 |

Note 7. This parameter is sampled and not 100% tested.

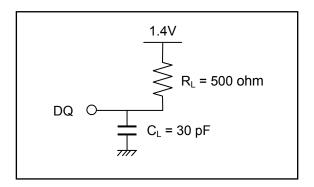
AC Characteristics

Test Conditions (Vcc = $2.4V \sim 3.6V$, Ta = $-40 \sim +85$ °C)

• Input pulse levels:

$$V_{IL} = 0.4V$$
, $V_{IH} = 2.4V$ (Vcc=2.7V to 3.6V)
 $V_{IL} = 0.4V$, $V_{IH} = 2.2V$ (Vcc=2.4V to 2.7V)

- Input rise and fall time: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



Read Cycle

| Parameter | Symbol | Vcc=2.7 | V to 3.6V | Vcc=2.4 | V to 2.7V | Unit | Note |
|------------------------------------|-------------------|---------|-----------|---------|-----------|-------|--------|
| Farameter | Symbol | Min. | Max. | Min. | Max. | Ullit | Note |
| Read cycle time | t _{RC} | 45 | - | 55 | _ | ns | |
| Address access time | t _{AA} | _ | 45 | _ | 55 | ns | |
| Chin coloct access time | t _{ACS1} | _ | 45 | _ | 55 | ns | |
| Chip select access time | t _{ACS2} | _ | 45 | _ | 55 | ns | |
| Output enable to output valid | t _{OE} | _ | 22 | _ | 30 | ns | |
| Output hold from address change | t _{OH} | 10 | _ | 10 | _ | ns | |
| Chin coloct to output in low 7 | t _{CLZ1} | 10 | _ | 10 | _ | ns | 8,9 |
| Chip select to output in low-Z | t _{CLZ2} | 10 | _ | 10 | _ | ns | 8,9 |
| Output enable to output in low-Z | t _{OLZ} | 5 | _ | 5 | _ | ns | 8,9 |
| Chin deceler to output in high 7 | t _{CHZ1} | 0 | 18 | 0 | 20 | ns | 8,9,10 |
| Chip deselect to output in high-Z | t _{CHZ2} | 0 | 18 | 0 | 20 | ns | 8,9,10 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 18 | 0 | 20 | ns | 8,9,10 |

Note 8. This parameter is sampled and not 100% tested.

- 9. At any given temperature and voltage condition, t_{CHZ1} max is less than t_{CLZ1} min, t_{CHZ2} max is less than t_{CLZ2} min, and t_{OHZ} max is less than t_{OLZ} min, for any device.
- 10. t_{CHZ1} , t_{CHZ2} and t_{OHZ} are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.

Write Cycle

| Darameter | Cumbal | Vcc=2.7 | V to 3.6V | Vcc=2.4 | V to 2.7V | Linit | Note |
|------------------------------------|------------------|---------|-----------|-----------|-----------|-------|-------|
| Parameter | Symbol | Min. | Max. | Min. Max. | | Unit | Note |
| Write cycle time | twc | 45 | _ | 55 | _ | ns | |
| Address valid to write end | t _{AW} | 35 | _ | 50 | _ | ns | |
| Chip select to write end | t _{CW} | 35 | _ | 50 | _ | ns | |
| Write pulse width | t _{WP} | 35 | _ | 40 | _ | ns | 11 |
| Address setup time to write start | t _{AS} | 0 | _ | 0 | _ | ns | |
| Write recovery time from write end | t _{WR} | 0 | _ | 0 | _ | ns | |
| Data to write time overlap | t _{DW} | 25 | _ | 25 | _ | ns | |
| Data hold from write end | t _{DH} | 0 | _ | 0 | _ | ns | |
| Output enable from write end tow | | 5 | _ | 5 | _ | ns | 12 |
| Output disable to output in high-Z | t _{OHZ} | 0 | 18 | 0 | 20 | ns | 12,13 |
| Write to output in high-Z | t _{WHZ} | 0 | 18 | 0 | 20 | ns | 12,13 |

Note 11. t_{WP} is the interval between write start and write end.

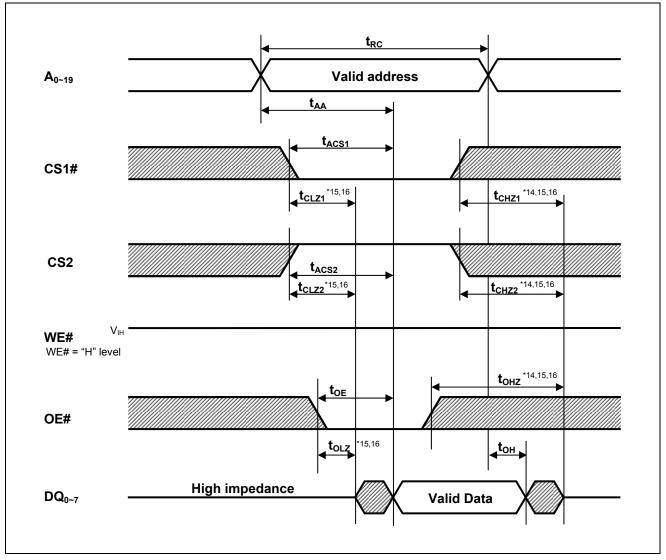
A write starts when all of (CS1#), (WE#) and (CS2) become active.

A write is performed during the overlap of a low CS1#, a low WE# and a high CS2.

- 12. This parameter is sampled and not 100% tested.
- 13. t_{OHZ} and t_{WHZ} are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.

Timing Waveforms

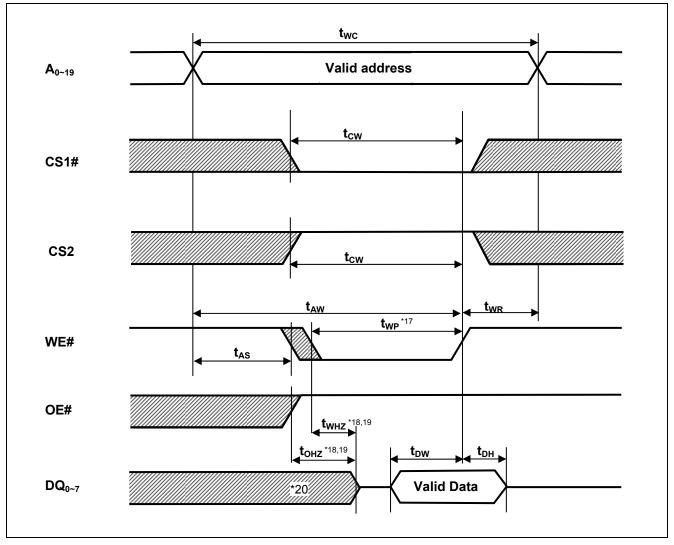
Read Cycle



Note 14. t_{CHZ1} , t_{CHZ2} and t_{OHZ} are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.

- 15. This parameter is sampled and not 100% tested
- 16. At any given temperature and voltage condition, t_{CHZ1} max is less than t_{CLZ1} min, t_{CHZ2} max is less than t_{CLZ2} min, and t_{OHZ} max is less than t_{OLZ} min, for any device.

Write Cycle (1) (WE# CLOCK, OE#="H" while writing)



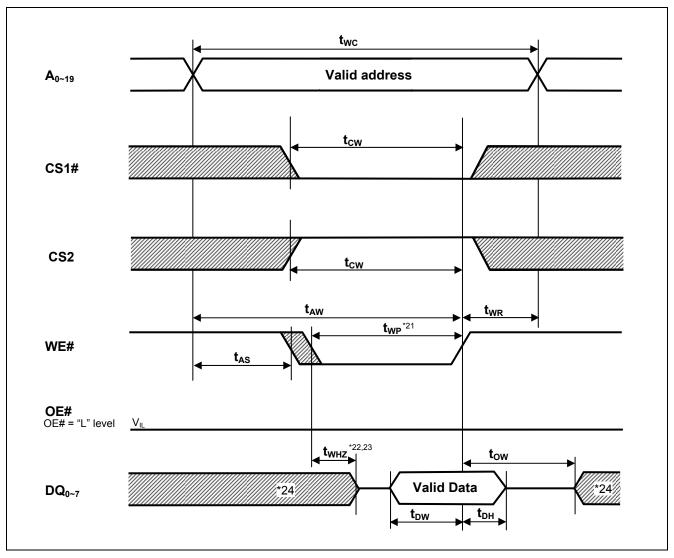
Note $\,$ 17. $\,$ t_{WP} is the interval between write start and write end.

A write starts when all of (CS1#), (WE#) and (CS2) become active.

A write is performed during the overlap of a low CS1#, a low WE# and a high CS2.

- 18. t_{OHZ} and t_{WHZ} are defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.
- 19. This parameter is sampled and not 100% tested
- 20. During this period, DQ pins are in the output state so input signals must not be applied to the DQ pins.

Write Cycle (2) (WE# CLOCK, OE# Low Fixed)



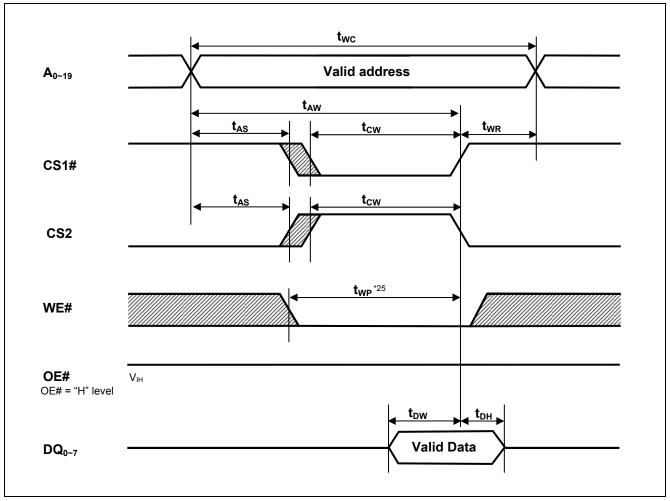
Note 21. t_{WP} is the interval between write start and write end.

A write starts when all of (CS1#), (WE#) and (CS2) become active.

A write is performed during the overlap of a low CS1#, a low WE# and a high CS2.

- 22. t_{WHZ} is defined as the time when the DQ pins enter a high-impedance state and are not referred to the DQ levels.
- 23. This parameter is sampled and not 100% tested.
- 24. During this period, DQ pins are in the output state so input signals must not be applied to the DQ pins.

Write Cycle (3) (CS1#, CS2 CLOCK)



Note $\,$ 25. $\,$ t_{WP} is the interval between write start and write end.

A write starts when all of (CS1#), (WE#) and (CS2) become active.

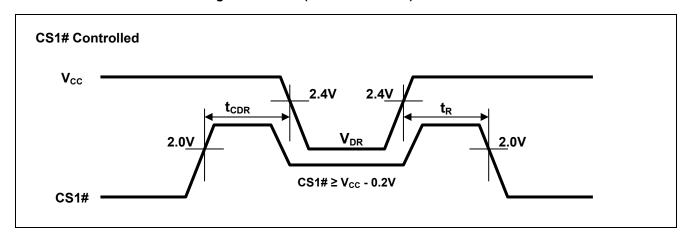
A write is performed during the overlap of a low CS1#, a low WE# and a high CS2.

Low V_{CC} Data Retention Characteristics

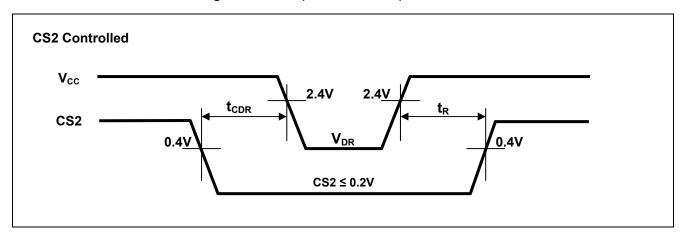
| Parameter | Symbol | Min. | Тур. | Max. | Unit | Test conditions ^{*28} | | |
|--------------------------------------|------------------|------|---------------------|------|------|--|--|--|
| V _{CC} for data retention | V_{DR} | 1.5 | _ | 3.6 | V | Vin ≥ 0V, (1) CS2 ≤ 0.2V or (2) CS1# ≥ V_{CC} -0.2V, CS2 ≥ V_{CC} -0.2 | | |
| | ICCDR | _ | 0.45 ^{*26} | 2 | μΑ | ~+25°C | | |
| | | _ | 0.6 ^{*27} | 4 | μΑ | ~+40°C | $V_{CC} = 3.0V$, Vin $\ge 0V$, (1) CS2 $\le 0.2V$ or | |
| Data retention current | | _ | _ | 7 | μΑ | ~+70°C | (2) CS1# ≥ V _{CC} -0.2V, CS2 ≥ V _{CC} -0.2V | |
| | | _ | _ | 10 | μΑ | ~+85°C | | |
| Chip deselect time to data retention | t _{CDR} | 0 | _ | _ | ns | See retention was aform | | |
| Operation recovery time | t _R | 5 | _ | _ | ms | See retention waveform. | | |

- Note 26. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=25°C), and not 100% tested.
 - 27. Typical parameter indicates the value for the center of distribution at 3.0V (Ta=40°C), and not 100% tested.
 - 28. CS2 controls address buffer, WE# buffer, CS1# buffer, OE# buffer and DQ buffer. If CS2 controls data retention mode, Vin levels (address, WE#, CS1#, OE#, DQ) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2 ≥ V_{CC}-0.2V or CS2 ≤ 0.2V. The other inputs levels (address, WE#, OE#, DQ) can be in the high-impedance state.

Low Vcc Data Retention Timing Waveforms (CS1# controlled)



Low Vcc Data Retention Timing Waveforms (CS2 controlled)



Revision History

RMLV0808BGSB Data Sheet

| | | Description | | | | | | |
|------|------------|-------------|--|--|--|--|--|--|
| Rev. | Date | Page | Summary | | | | | |
| 1.00 | 2014.11.28 | _ | First Edition issued | | | | | |
| 2.00 | 2015.06.26 | P.1, 4 | Standby current I _{SB1} : 25°C 0.6μA ->0.45μA (typ.), 40°C 2μA ->0.6μA (typ.) | | | | | |
| | | P.2 | Modefy Pin Arrangement : Add 1pin Mark | | | | | |
| | | P.4 | Average operating current I _{CC2} : 25°C 2mA ->1.5mA (typ.) | | | | | |
| | | P.11 | Data retention current I _{CCDR} : 25°C 0.6μA ->0.45μA (typ.), 40°C 2μA ->0.6μA (typ.) | | | | | |
| | | | | | | | | |

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Renesas Electronics America Inc. 2801 Scott Boulevard Santa Clara, CA 95050-2549, U.S.A. Tel: +1-408-588-6000, Fax: +1-408-588-6130

Renesas Electronics Canada Limited 9251 Yonge Street, Suite 8309 Richmond Hill, Ontario Canada L4C 9T3 Tel: +1-905-237-2004

Renesas Electronics Europe Limited Dukes Meadow, Millboard Road, Bourne End, Buckinghamshire, SL8 5FH, U.K Tel: +44-1628-585-100, Fax: +44-1628-585-900

Renesas Electronics Europe GmbH

Arcadiastrasse 10, 40472 Düsseldorf, Germany Tel: +49-211-6503-0, Fax: +49-211-6503-1327

Renesas Electronics (China) Co., Ltd.
Room 1709, Quantum Plaza, No.27 ZhiChunLu Haidian District, Beijing 100191, P.R.China Tel: +86-10-8235-7679

Renesas Electronics (Shanghai) Co., Ltd.
Unit 301, Tower A, Central Towers, 555 Langao Road, Putuo District, Shanghai, P. R. China 200333
Tel: 486-21-2226-0888, Fax: +86-21-2226-0999

Renesas Electronics Hong Kong Limited
Unit 1601-1611, 16/F., Tower 2, Grand Century Place, 193 Prince Edward Road West, Mongkok, Kowloon, Hong Kong
Tel: +852-2865-6688, Fax: +852 2886-9022

Renesas Electronics Taiwan Co., Ltd. 13F, No. 363, Fu Shing North Road, Taipei 10543, Taiwan Tel: +886-2-8175-9600, Fax: +886 2-8175-9670

Renesas Electronics Singapore Pte. Ltd. 80 Bendemeer Road, Unit #06-02 Hyflux Innovation Centre, Singapore 339949 TE: +65-6213-0200, Fax: +65-6213-0300

Renesas Electronics Malaysia Sdn.Bhd.
Unit 1207, Block B, Menara Amcorp, Amcorp Trade Centre, No. 18, Jln Persiaran Barat, 46050 Petaling Jaya, Selangor Darul Ehsan, Malaysia Tei: +60-3-7955-9390, Fax: +60-3-7955-9510

Renesas Electronics India Pvt. Ltd.
No.777C, 100 Feet Road, HALII Stage, Indiranagar, Bangalore, India Tel: +91-80-67208700, Fax: +91-80-67208777

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